MOSFET - Power, N-Channel, Shielded Gate 40 V, 2.75 mΩ, 104 A

NTTFS2D8N04HL

General Description

This N-Channel MOSFET is produced using ON Semiconductor's advanced MOSFET process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 2.75 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 16 \text{ A}$
- Max $r_{DS(on)} = 4.3 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 13 \text{ A}$
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

Applications

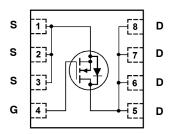
- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive



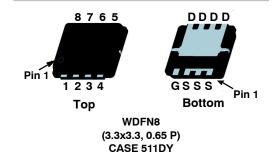
ON Semiconductor®

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ELECTRICAL CONNECTION



N-Channel MOSFET



MARKING DIAGRAM



 04HL
 = Device Code

 A
 = Assembly Location

 Y
 = Year Code

 WW
 = Work Week Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

$\textbf{MOSFET MAXIMUM RATINGS} \ (T_A = 25^{\circ}C \ unless \ otherwise \ noted)$

Symbol		Para	Ratings	Unit		
V _{DS}	Drain to Source Voltage				40	V
V _{GS}	Gate to Source \	/oltage			±20	V
I _D	Drain Current	-Continuous	T _C = 25°C	(Note 5)	104	Α
		-Continuous	T _C = 100°C	(Note 5)	66	
		-Continuous	T _A = 25°C	(Note 1a)	24	
		-Pulsed		(Note 4)	216	
E _{AS}	Single Pulse Ava	alanche Energy		(Note 3)	109	mJ
P _D	Power Dissipation T _C =		T _C = 25°C		63	W
	Power Dissipation	n	T _A = 25°C	(Note 1a)	3.2	1
T _J , T _{STG}	Operating and Storage Junction Temperature Range				-55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case	2	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	39	

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
04HL	NTTFS2D8N04HL	WDFN8 (3.3x3.3)	7"	12 mm	1500 Units

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
FF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C		22		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 32 V, V _{GS} = 0 V			10	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = +20 V, V _{DS} = 0 V			100	nA
N CHARACTE	ERISTICS					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 80 \mu A$	1.2	1.6	2.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 80 μA, referenced to 25°C		-4.9		mV/°C
r _{DS(on)}	Static Drain to Source On	V _{GS} = 10 V, I _D = 16 A		2.4	2.75	mΩ
	Resistance	V _{GS} = 4.5 V, I _D = 13 A		3.4	4.3	7
YNAMIC CHA	RACTERISTICS					
C _{ISS}	Input Capacitance	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V},$		1960		pF
C _{OSS}	Output Capacitance	f = 1 MHz		460		
C _{RSS}	Reverse Transfer Capacitance			30		7
R_{G}	Gate Resistance			0.8		Ω

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

Parameter	Test Condit	ions	Min	Tvp	Max	Units
ARACTERISTICS				1 -71		
Turn – On Delay Time	V_{DD} = 20 V, I_{D} = 16 A, V_{GS} = 10 V, R_{GEN} = 2.5 Ω			7.5		ns
Rise Time				16.6		
Turn – Off Delay Time			30			
Fall Time	1			2.8		
Total Gate Charge	V _{GS} = 0V to 10 V			32		nC
Total Gate Charge	V _{GS} = 0V to 4.5 V			15		
Gate to Source Charge	V _{DD} = 20 V I _D = 16 A			5.6		
Gate to Drain "Miller" Charge				3.4		
E DIODE CHARACTERISTICS						
Source to Drain Diode Forward	V _{GS} = 0 V, I _S = 16 A (Note 2)			0.78	1.2	V
voitage	$V_{GS} = 0 \text{ V}, I_{S} = 16 \text{ A}$	(Note 2)		0.63	1.3	
	ARACTERISTICS Turn – On Delay Time Rise Time Turn – Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Charge Gate to Drain "Miller" Charge E DIODE CHARACTERISTICS	Turn - On Delay Time	ARACTERISTICS Turn – On Delay Time Rise Time Turn – Off Delay Time Fall Time Total Gate Charge Gate to Source Charge Gate to Drain "Miller" Charge Folion Example Source to Drain Diode Forward VDD = 20 V, ID = 16 A, VGS = 10 V, RGEN = 2.5 Ω VGS = 10 V, RGEN = 2.5 Ω VGS = 0 V to 10 V VGS = 0 V to 4.5 V VDD = 20 V ID = 16 A	Turn – On Delay Time Rise Time Turn – Off Delay Time Fall Time Total Gate Charge Gate to Source Charge Gate to Drain "Miller" Charge E DIODE CHARACTERISTICS VDD = 20 V, ID = 16 A, VGS = 10 V, RGEN = 2.5 \(\Omega\) VGS = 0V to 10 V VDD = 20 V ID = 16 A VDD = 20 V ID = 16 A VGS = 0V to 4.5 V	ARACTERISTICS Turn – On Delay Time $V_{DD} = 20 \text{ V}, I_D = 16 \text{ A}, V_{GS} = 10 \text{ V}, R_{GEN} = 2.5 \Omega$ Fall Time $V_{DS} = 10 \text{ V}, R_{GEN} = 2.5 \Omega$ Total Gate Charge $V_{GS} = 0 \text{ V} to 10 \text{ V}$ Gate to Source Charge $V_{GS} = 0 \text{ V} to 4.5 \text{ V}$ Gate to Drain "Miller" Charge $V_{GS} = 0 \text{ V}, I_S = 16 \text{ A}$ E DIODE CHARACTERISTICS Source to Drain Diode Forward Voltage	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

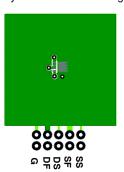
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

 $I_F = 16 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$

 t_{rr}

 Q_{rr}

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 \times 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



a) 53°C/W when mounted on a 1 in² pad of 2 oz copper.

Reverse Recovery Time

Reverse Recovery Charge



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

32.2

27.4

ns

nC

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3. E_{AS} of 109 mJ is based on starting T_J = 25 °C; L = 0.3 mH, I_{AS} = 27 A, V_{DD} = 32 V, V_{GS} = 10 V. 100% test at L = 0.3 mH, I_{AS} = 27 A.
- 4. Pulsed I_D please refer to SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

TYPICAL CHARACTERISTICS

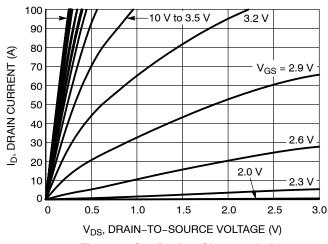


Figure 1. On-Region Characteristics

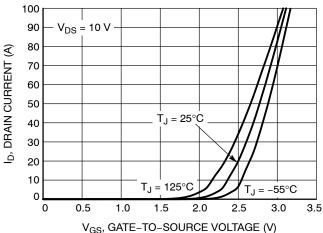


Figure 2. Transfer Characteristics

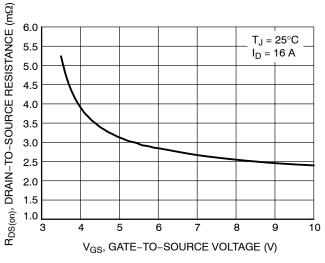


Figure 3. On-Resistance vs. Gate-to-Source Voltage

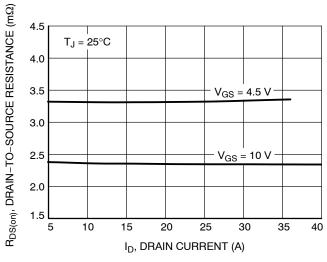


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

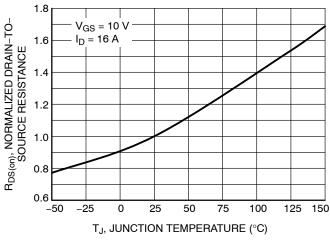


Figure 5. On–Resistance Variation with Temperature

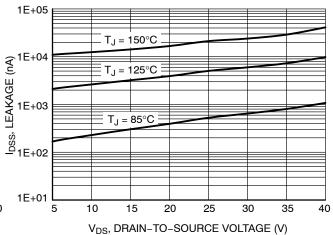


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

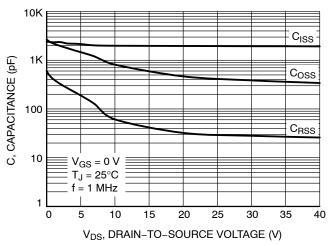


Figure 7. Capacitance Variation

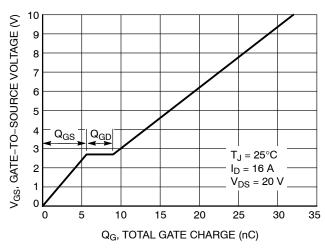


Figure 8. Gate-to-Source Voltage vs. Total Charge

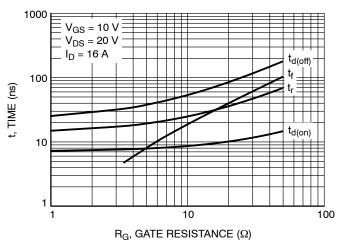


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

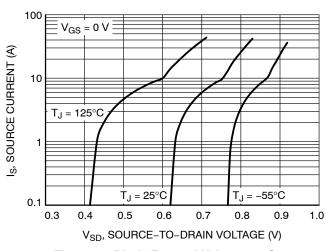


Figure 10. Diode Forward Voltage vs. Current

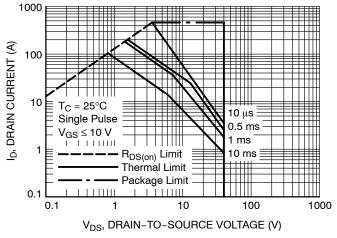


Figure 11. Maximum Rated Forward Biased Safe Operating Area

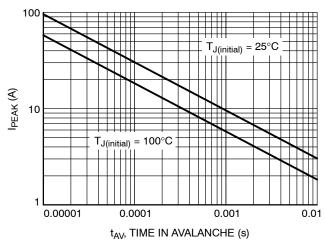


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

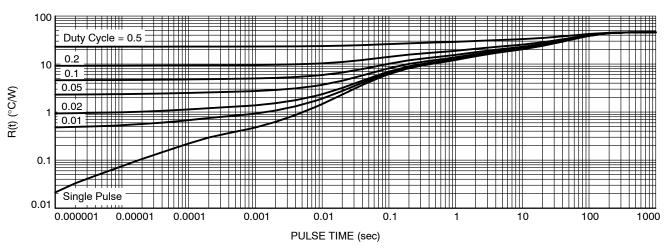
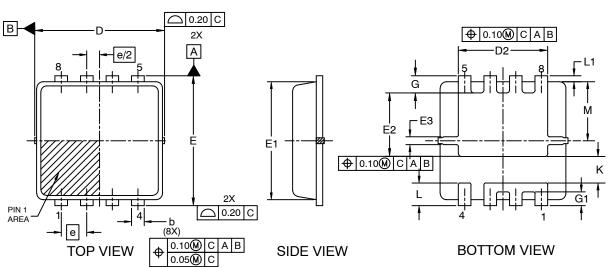


Figure 13. Transient Thermal Impedance

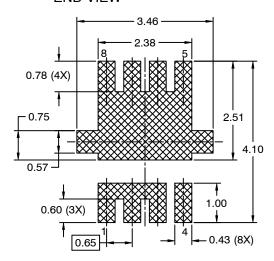
PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65PCASE 511DY ISSUE A



(4X) Θ D1 Α // 0.10 C A1 (8X) C SEATING PLANE

END VIEW



RECOMMENDED LAND PATTERN

NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETERS
- 2. DIMENSIONS D1 & E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.

DIM	MILLIMETERS					
DIIVI	MIN	NOM	MAX			
Α	0.70	0.75	0.80			
A1	0.00	-	0.05			
b	0.23	0.33	0.43			
C	0.15	0.20	0.25			
D	3.20	3.30	3.40			
D1	2.95	3.13	3.30			
D2	1.98	2.20	2.40			
Е	3.20	3.30	3.40			
E1	2.80	3.00	3.15			
E2	1.40	1.60	1.80			
E3	0.15	0.25	0.40			
е	0.65 BSC					
G	0.30	0.43	0.55			
G1	0.25	0.35	0.45			
K	0.55	0.75	0.95			
L	0.35	0.52	0.65			
L1	0.06	0.15	0.30			
М	1.35	1.50	1.60			
θ	0	-	12			

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